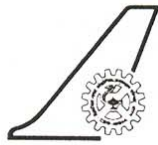


Documentation Sheet



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Abstract

Chiral materials have potential applications in the design of radomes, microstrip substrates, phase shifters, radar absorbers etc. This necessitates the accurate measurement of EM material parameters of chiral materials. In this report, various EM material characterization techniques for chiral media are discussed in detail. These techniques are mainly based on free-space and waveguide methods. Details of theoretical aspects, experimental set-ups and measurement procedures are included for each method.